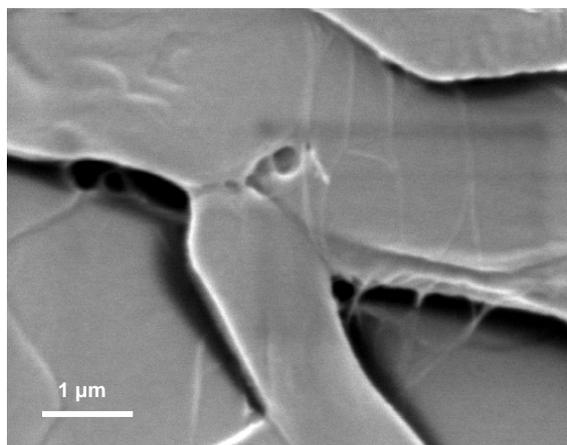
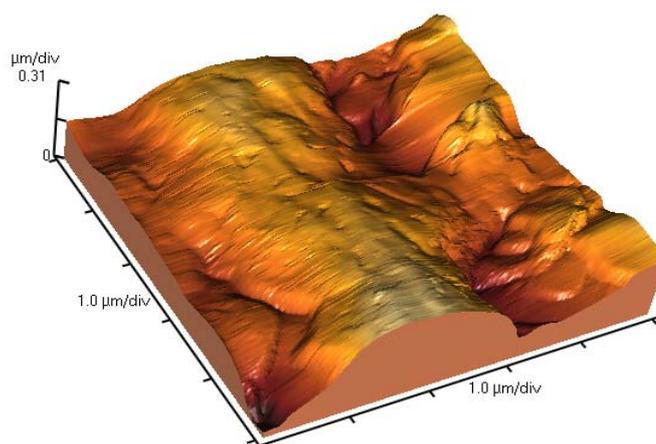


## Supporting Information

Figure S1: A drop of nanotube suspension was air-dried onto a silicon wafer for SEM and AFM measurements. (a) SEM image. The nanotubes were mostly concealed in the dried surfactant layer. (b) AFM image (measured on a different location). The thickness of surfactant layer was on the order of 400 nm.



(a) SEM image



(b) AFM image